

# N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A)		
60	0.028 at V <sub>GS</sub> = 10 V	8.5		
00	0.031 at V <sub>GS</sub> = 4.5 V	7.9		

### **FEATURES**

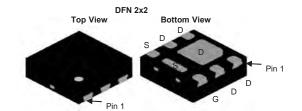
- DT-Trench Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC

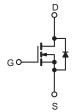


ROHS

### **APPLICATIONS**

- Primary Side Switch
- Synchronous Rectification





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b>	$T_A = 25$ °C, unles	ss otherwise n	oted			
Parameter	Symbol	10 s	Steady State	Unit		
Drain-Source Voltage		V <sub>DS</sub>	60		V	
Gate-Source Voltage		V <sub>GS</sub>	± 20			
Continuous Drain Current (T = 150 °C)	T <sub>A</sub> = 25 °C		8.5	6.0		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 70 °C	l <sub>D</sub>	7.6	4.8		
Pulsed Drain Current		I <sub>DM</sub>	40		А	
Continuous Source Current (Diode Conduction) <sup>a</sup>		I <sub>S</sub>	3.2	1.3		
Single Avalanche Current	nche Current L = 0.1 mH		22			
Single Avalanche Energy	L=0.1 IIII	E <sub>AS</sub>	24		mJ	
Maximum Power Dissipation <sup>a</sup>	T <sub>A</sub> = 25 °C	В	3.8	1.5	W	
Maximum Power Dissipation.	T <sub>A</sub> = 70 °C	P <sub>D</sub>	2.4	1.0	VV	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150		°C	
Soldering Recommendations (Peak Temperature) <sup>b, c</sup>			260			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a</sup>	t ≤ 10 s	В	26	33		
waximum sunction-to-Ambient	Steady State	- R <sub>thJA</sub>	65	81	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	1.9	2.4	1	

#### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. The DFN2X2 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- c. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.5	2.5	3.0	V	
Gate Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	1	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V			1	μA	
Zero Gate Voltage Brain Garrent	I <sub>DSS</sub>	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			5	μΛ	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_D = 8.5 \text{ A}$	I <sub>D</sub> = 8.5 A		0.031	Ω	
Drain-Source On-State Resistance		$V_{GS} = 4.5 \text{ V}, I_D = 6.9 \text{ A}$		0.031	0.034	52	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 8.5 \text{ A}$		35		S	
Diode Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>S</sub> = 3.2 A, V <sub>GS</sub> = 0 V		0.78	1.2	V	
Dynamic <sup>b</sup>							
Total Gate Charge	Qg			30	45		
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 8.5 \text{ A}$		6.9		nC	
Gate-Drain Charge	$Q_{gd}$			5.8			
Gate Resistance	R <sub>g</sub>		0.65	1.3	1.95	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			14	25		
Rise Time	t <sub>r</sub>	$V_{DD} = 30 \text{ V}, R_{L} = 30 \Omega$		12	20		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 6 \Omega$		50	80	ns	
Fall Time	t <sub>f</sub>			12	20	1	
Source-Drain Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 3.2 A, dl/dt = 100 A/μs		60	100	1	

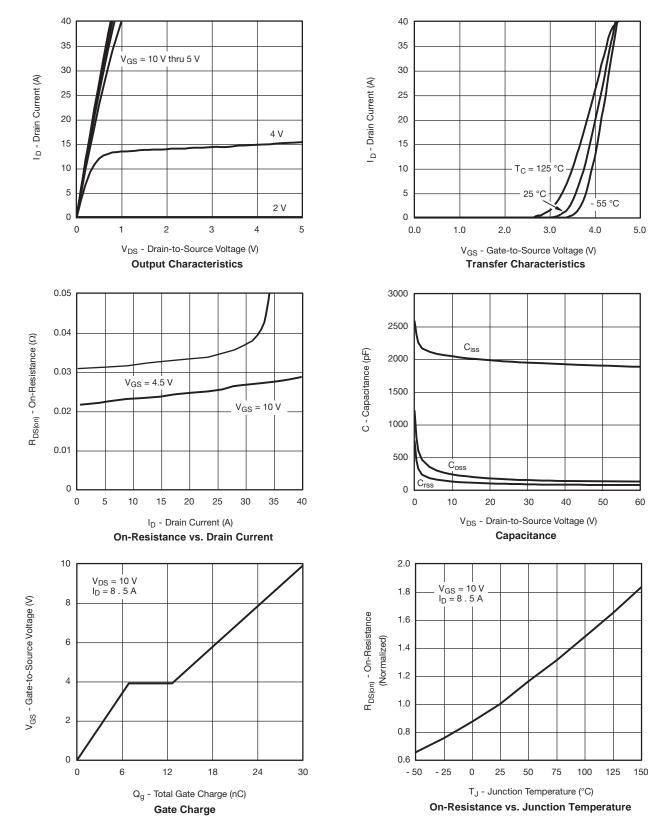
- a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



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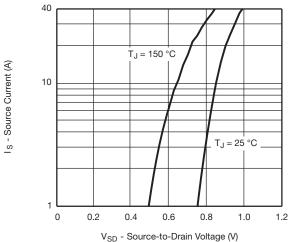
### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



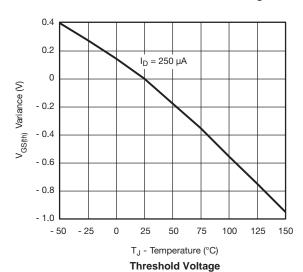


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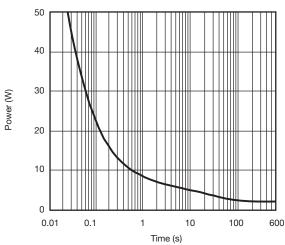


Source-Drain Diode Forward Voltage

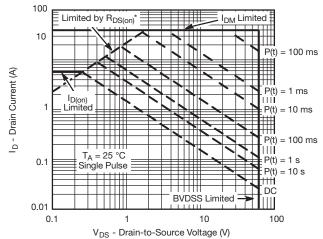


0.10 I<sub>D</sub> = 8 . 5 A 0.08 0.06 0.04 0.02 0.00 0 2 4 6 8 10

 $\label{eq:VGS} V_{GS} \text{ - Gate-to-Source Voltage (V)} \\$  On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient



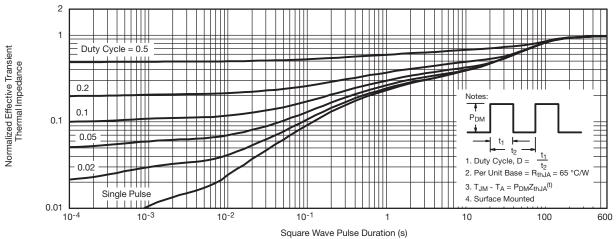
\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area

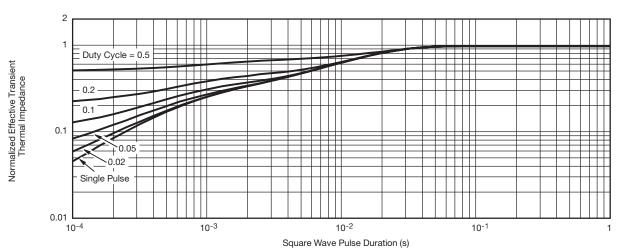


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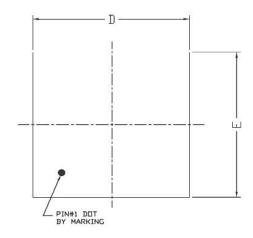
Normalized Thermal Transient Impedance, Junction-to-Ambient

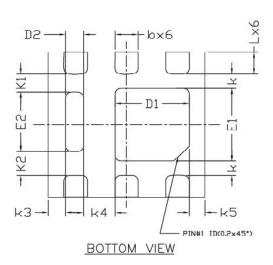


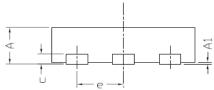
Normalized Thermal Transient Impedance, Junction-to-Case

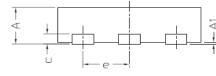


## DFN2x2 \_6L\_EP1\_S PACKAGE OUTLINE









RECOMMENDED LAND PATTERN

0.650	0.300 000
2.050	-0.820 -0.330 -1.725

0.400--1.600-

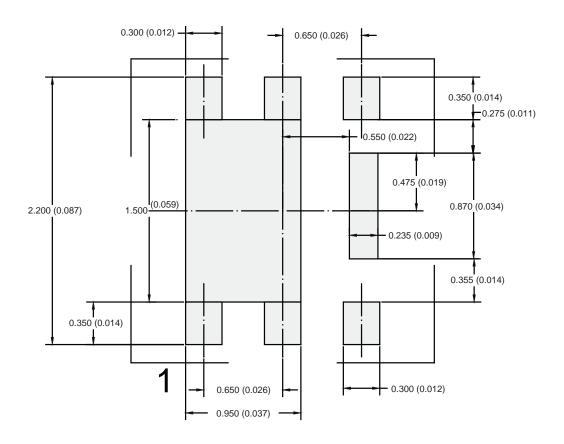
SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.50	0. 55	0.60	0.020	0.022	0.024
A1	0.00		0.05	0.000		0.002
ь	0.25	0.30	0.35	0.010	0.012	0.014
С		0.152 REF		0.006 REF		
D	1.90	2.00	2.10	0.075	0.079	0.083
D1	0.85	0.95	1.05	0.033	0.037	0.041
D2	0.13	0.23	0.33	0.005	0.009	0.013
E	1.90	2.00	2.10	0.075	0.079	0.083
E1	0.90	1.00	1.10	0.035	0.039	0.043
E2	0.72	0.82	0.92	0.028	0.032	0.036
e	0.65 BSC			0.026 BSC		
K	0. 20 BSC			0.008 BSC		
K1	0. 25 BSC			0.010 BSC		
K2	0. 33 BSC				0.013 BSC	
K3	0. 22 BSC			0.009 BSC		
K4	0.40 BSC			0. 016 BSC		
K5	0. 20 BSC			0.008 BSC		
L	0.25	0.30	0.35	0.010	0.012	0.014

### NOTE

CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm

### **RECOMMENDED PAD LAYOUT FOR DFN2X2**



Dimensions in mm/(Inches)



# Din-Tek SEMICONDUCTOR

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